

Device Modeling Report

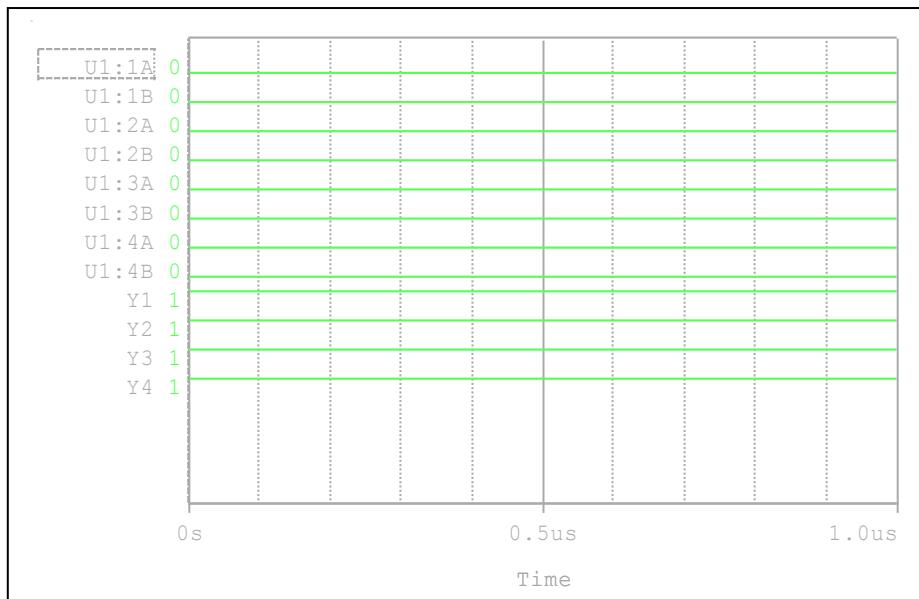
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC74HCT00AP
MANUFACTURER : TOSHIBA



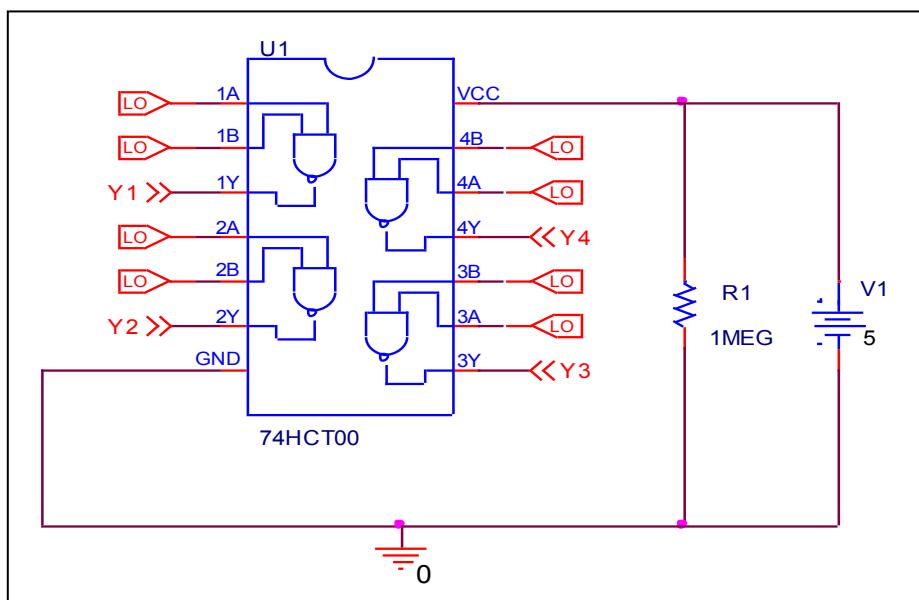
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

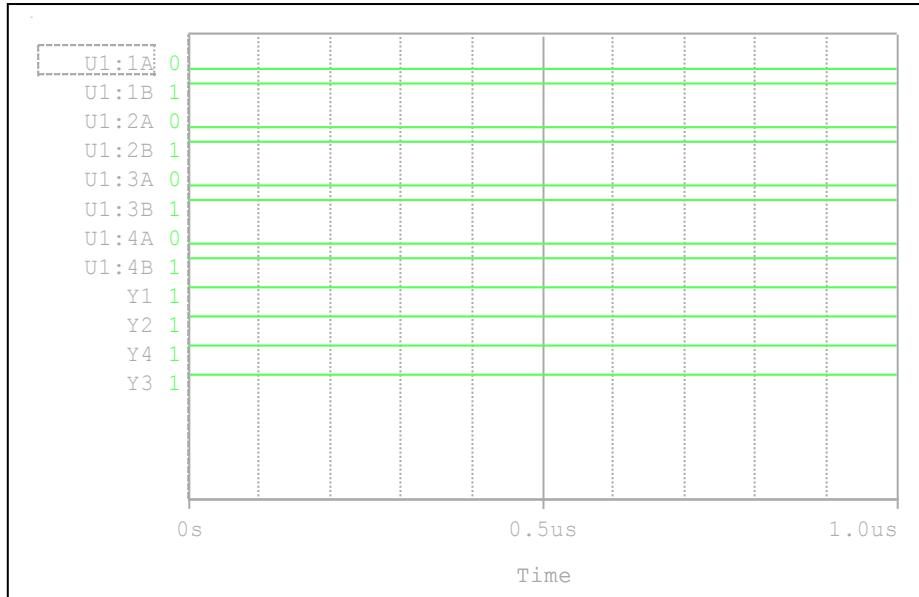


Comparison table

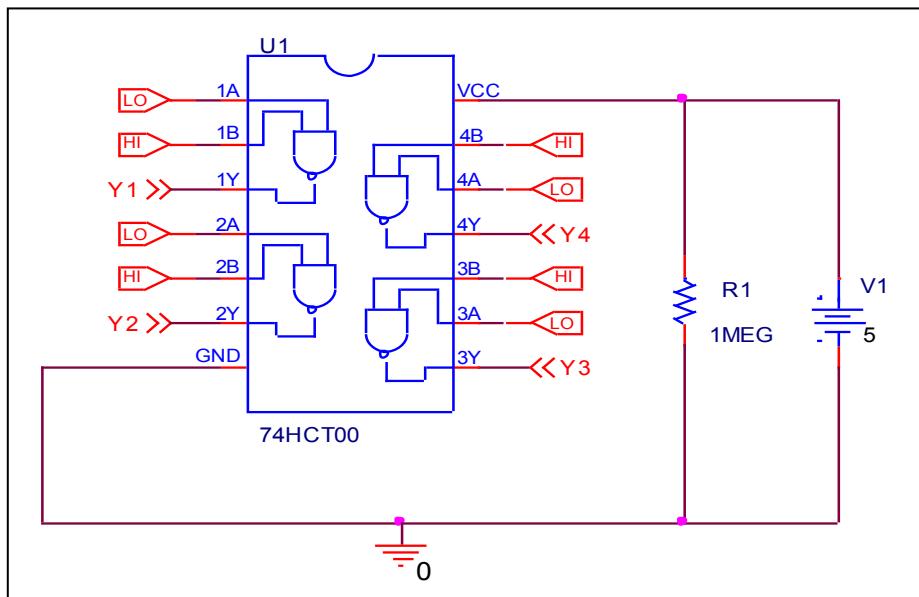
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

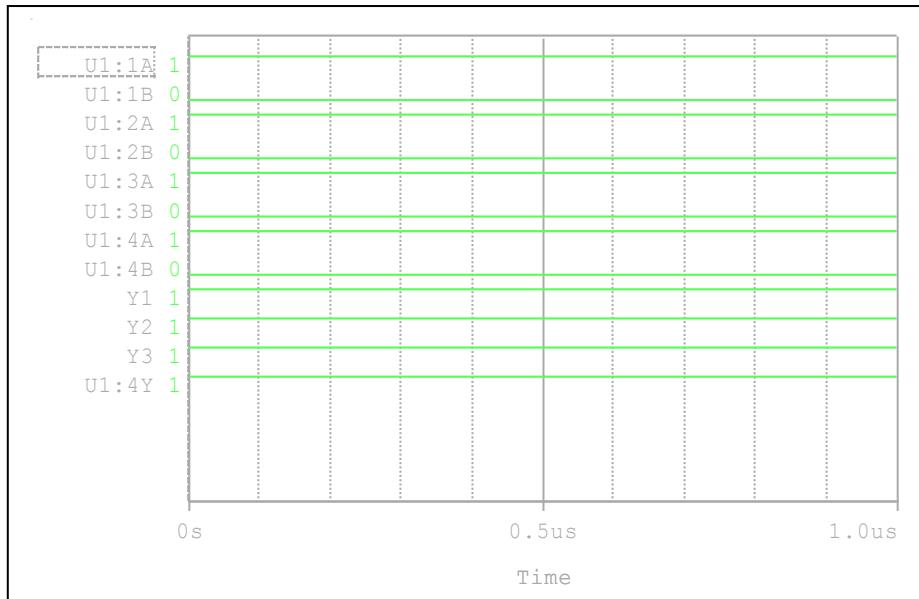


Comparison table

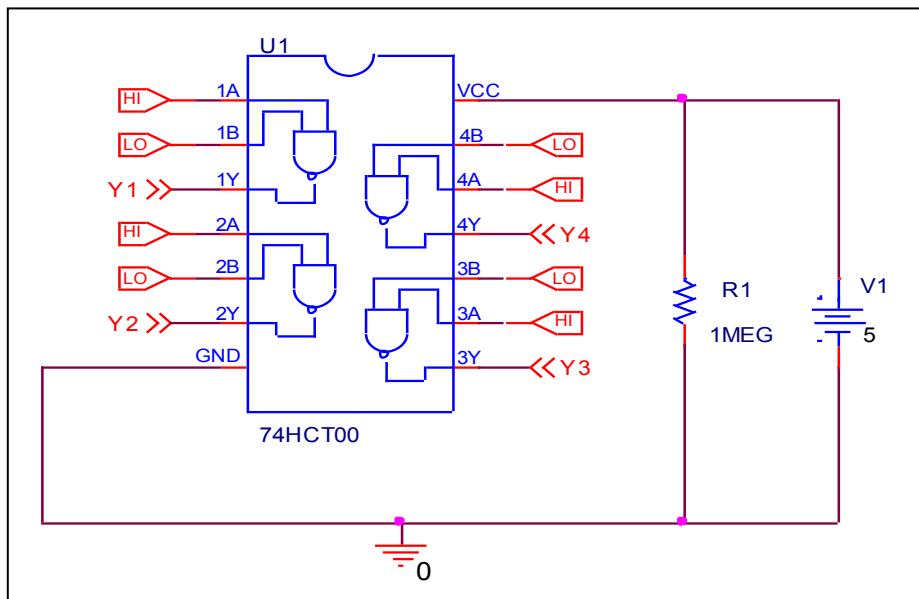
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
L	H	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

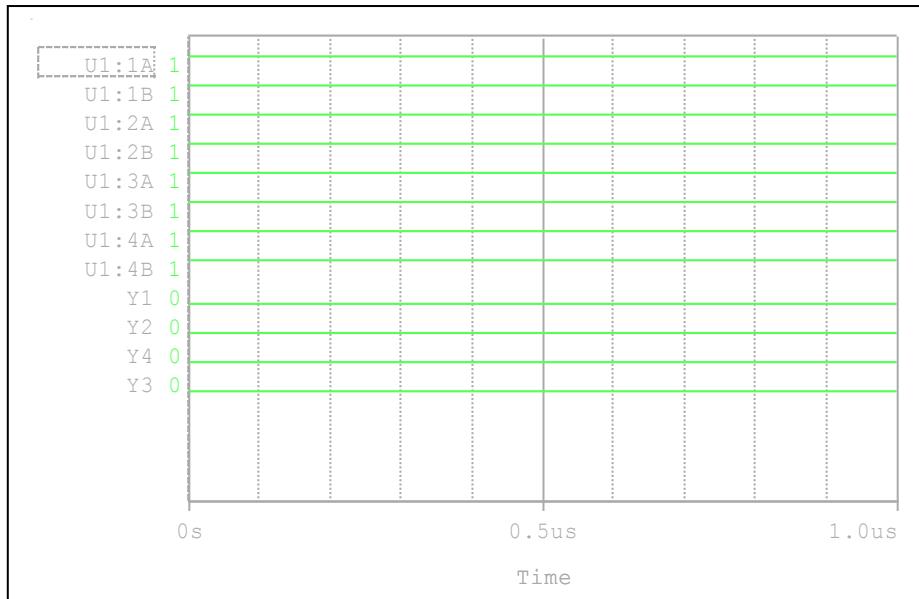


Comparison table

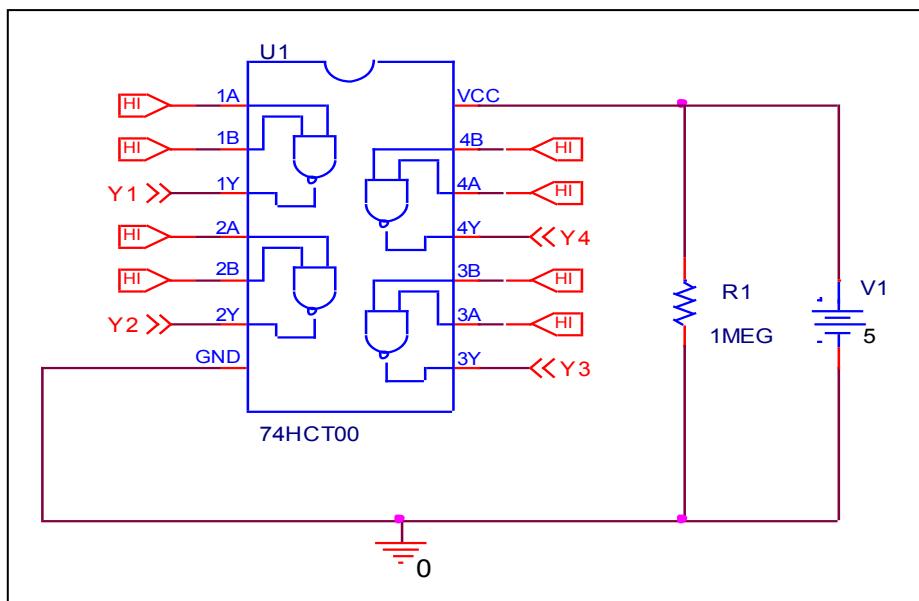
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

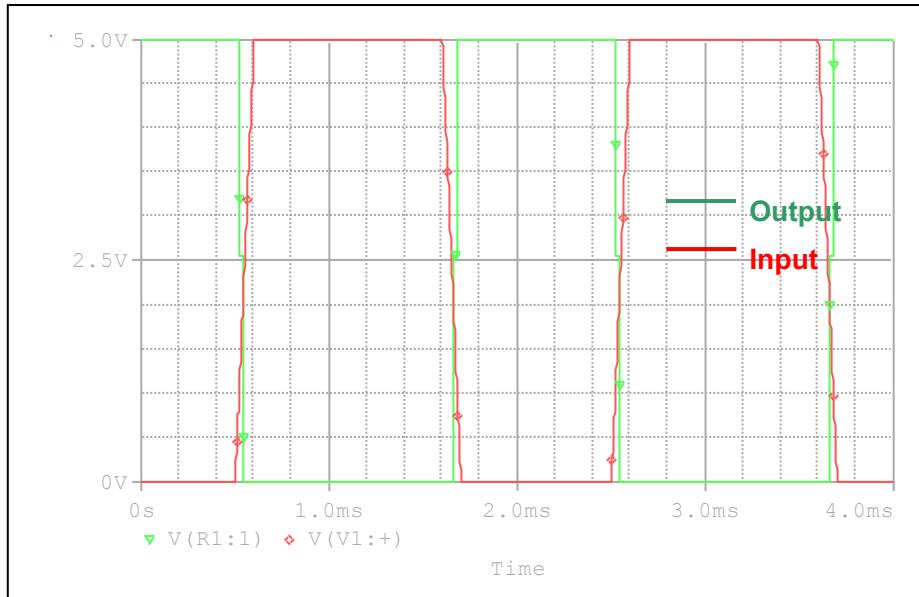


Comparison table

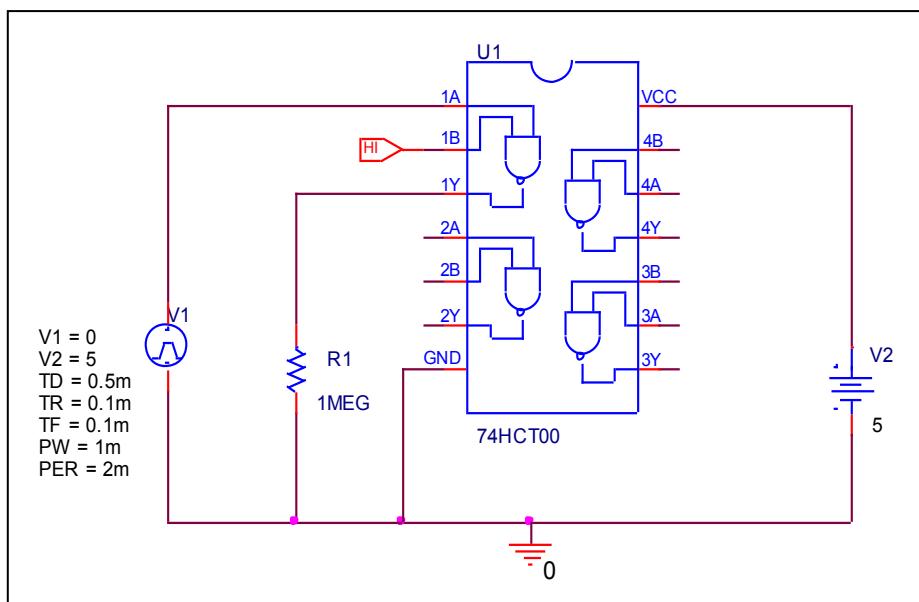
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	H	L	L	0

High Level and Low Level Input Voltage

Circuit simulation result



Evaluation circuit

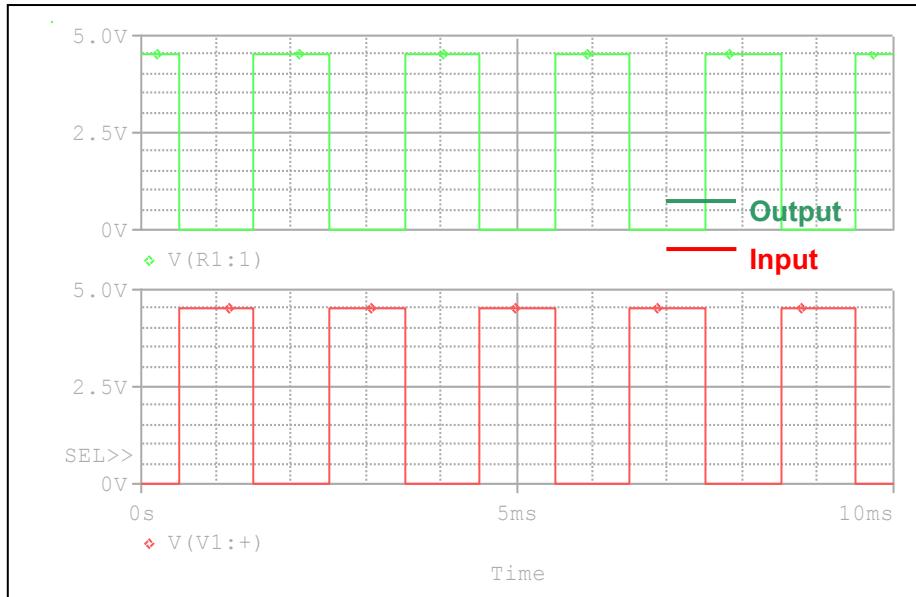


Comparison table

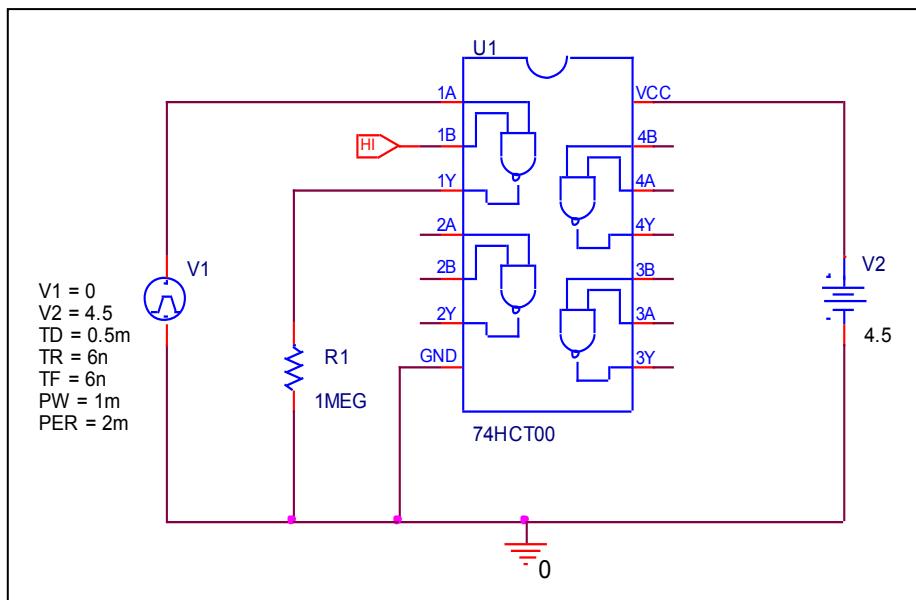
$V_{cc} = 5V$	Measurement	Simulation	%Error
$V_{IH} (V)$	2	2	0
$V_{IL} (V)$	0.8	0.799234	-0.096

High Level and Low Level Output Voltage

Circuit simulation result



Evaluation circuit

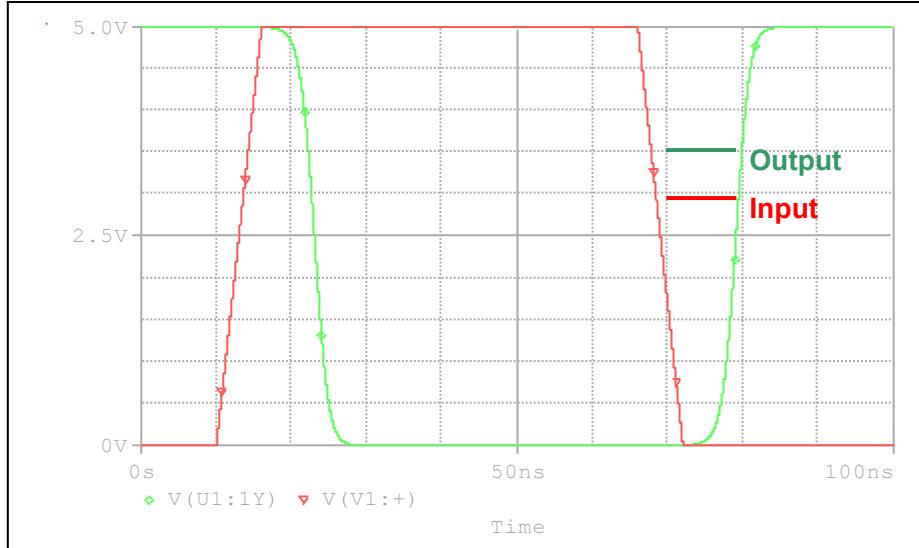


Comparison table

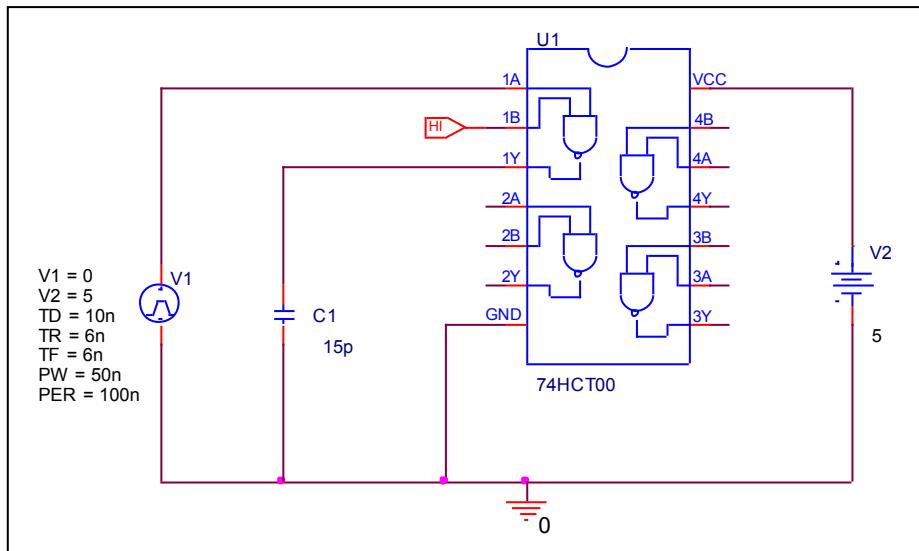
V _{CC} = 4.5V	Measurement	Simulation	%Error
V _{OH} (V)	4.5	4.4977	-0.051
V _{OL} (V)	0	0	0

Propagation Delay Time

Circuit simulation result



Evaluation circuit



Comparison table

$C_L=15\text{pF}, V_{CC}=5\text{V}, t_r=t_f=6\text{ns}$	Measurement	Simulation	%Error
$t_{TLH} (\text{ns})$	4	4.0133	0.333
$t_{THL} (\text{ns})$	4	4.0011	0.028
$T_{pLH} (\text{ns})$	10	10.072	0.720
$T_{pHL} (\text{ns})$	10	10.041	0.410